Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1981	soliton\$1 or fusiton\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/14 14:50
L2	693829	overlap\$5 or over adj lap\$5 or "over-lapping" or "over-lap"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/14 14:51
L3	14128	2 with pulse\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/14 14:51
L4	163	1 and 3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/14 16:39
L5	4	(("5095487"):or:("5872783")):PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/14 16:13
L6	2	"200056024"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/14 16:22
L7	2	"200137495"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/14 16:22
L8	5022	ultrashort or ultra adj short	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/14 16:39
L9	569	8 near3 (laser adj pulse\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/14 16:40
L10	35	1 and 9	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/14 16:47
L111	28	9 with modulat\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/14 16:47



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- · Run a search

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#	1 ((alfano and ultrashort) <in>metadata)</in>	5			
#	2 ((alfano and ultrashort) <in>metadata)</in>	5			
#	3 ((alfano and ultrashort) <in>metadata)</in>	5			
#	(((ultrashort or ultra short) and laser pulse and soliton) <in>metadata)</in>	6			
<u>#</u>	5 (((ultrashort or ultra short) and laser pulse and soliton) <in>metadata)</in>	6			



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